

RIEGL at FDIAI Conference

RIEGL USA will be participating to the trade show during the 2013 54th Annual Florida Division of the International Association for Identification (FDIAI) Conference. The 2013 54th Annual FDIAI Conference will be held at the Miami Downtown Hilton in Miami, Florida from 20 to 24 October 2013.

RIEGL USA will be exhibiting at Booth 4 during the conference. Representatives are available for any questions about hardware and software solutions and see demonstrations with one of the VZ-400 terrestrial laser scanners (also see video below).



<https://www.gim-international.com/content/news/riegl-at-fdai-conference>
